

Notice of References Cited	Application/Control No. 10/572,752	Applicant(s)/Patent Under Reexamination NAKAMURA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0113747	08-2002	Tessier et al.	343/787
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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